Search Notes						

Application/Control No.	Applicant(s)/Patent under Reexamination
09/666,271	SEKIYA ET AL.
Examiner	Art Unit
Hai C. Pham	2861

	SEAR	CHED	
Class	Subclass	Date	Examiner
347	236-238, 246-247	3/31/2005	НР
710	54-56, 58	3/31/2005	НР
719	314	3/31/2005	НР

INI	ERFERENC	CE SEARCH	ED
Class	Subclass	Date	Examiner
347	237, 247	3/31/2005	НР
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EAST TEXT SEARCH	3/31/2005	НР